

U.S. Department of Commerce, Patent and Trademark	Atty. Docket No.	Application No.
INFORMATION DISCLOSURE/STATEMENT BY APPLICANT	SENS.008US3	10/718,269
(Use several sheets if necessary)	Applicant(s)	Conf. No.
(Form PTO-1449)	Wayne Glenn RENKEN et al.	9982
	Filing Date	Group
	November 19, 2003	2829

U.S. Patent Documents

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
J. m. H.	1	6,691,068 B1	02/10/2004	FREED et al.	702	187

U.S. Published Patent Application Documents

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J. m. H.	2	2003/0223057 A1	12/04/2003	RAMSEY et al.	356	147
	3	2004/0267501 A1	12/30/2004	FREED et al.	702	184

Foreign Patent Documents

							Translation	
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Examiner *J. m. H.* Date Considered *8/3/05*

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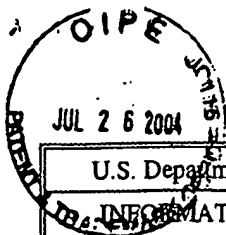
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g. n. H.	1	"Notification of Transmittal of the International Search Report or the Declaration", corresponding to PCT/US03/37836, International Searching Authority, European Patent Office, 27/09/2004, 6 pages.
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Examiner *John n. H. H. H.* Date Considered *7/26/05*

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J.m.H.	2	2002/0148307	Oct. 17, 2002	Jonkers			

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J.m.H.	3	WO 03/067183	Aug. 14, 2003	WIPO			✓	

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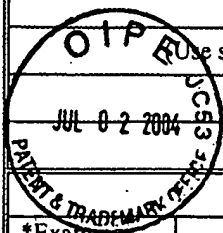
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Examiner J.m.H.

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	15	6,377,130	Apr. 23, 2002	Haman			
	16	6,378,378	Apr. 30, 2002	Fisher			
	17	6,472,240	Oct. 29, 2002	Akram et al.			
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9-14 ↓	27	WO00/68986	Nov. 16, 2000	WIPO	↓	↓	Abstract	/
	28	EP 1014437 A2	Jun. 28, 2000	Europe				
	29	WO02/17030A2	Feb. 28, 2002	WIPO				
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9-14 ↓	31	Prov. Pat. App. No. 60/285,613 filed 4/19/01; Freed et al.; "Firmware, Methods, Apparatus, and Computer Program Products for Wafer Sensors"						
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Examiner <i>Joe n. Hight</i>			Date Considered <i>7/26/05</i>					
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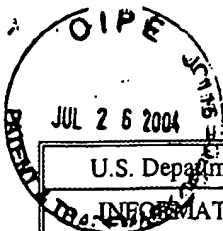
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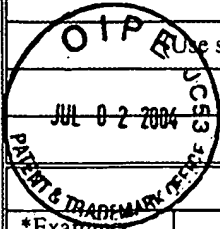
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